

Notic of References Cited	Application/Control No. 09/469,652		Applicant(s)/Patent Under Reexamination WIERER ET AL.	
	Examiner B. William Baumeister		Art Unit 2815	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	C	US-6,486,499	11-2002	Krames et al.	257/81
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	U	Brown et al., "Ohmic contacts to Si-implanted and un-implanted n-type GaN," Mat. Res. Soc. Symp. Proc. Vol. 395, 1996 Materials Research Society, pp. 855-860.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.